Headset Detection Interface

The NCS2300 is a compact and cost effective headset detection interface IC. It integrates a comparator, OR gate, and N-channel MOSFET to detect the presence of a stereo headset with a microphone. Pull-up resistors for the detection pins are internalized. A built in resistor divider provides the reference voltage for detecting the left audio channel. The logic low output of the OR gate indicates the headset has been connected properly. The NCS2300 comes in a space saving UDFN6 package (1.2 x 1.0 mm).

Features

- Supply Voltage: 1.6 V to 2.75 V
- Low Quiescent Supply Current: 7.5 μ A typical @ V_{DD} = 1.8 V
- Integrated Resistors, Comparator, OR Gate, and N–Channel MOSFET
- Space Saving UDFN6 Package
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

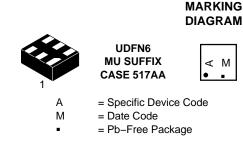
Typical Applications

- Cell Phones, Smartphones
- Tablets
- Notebooks

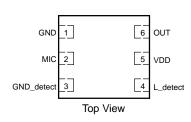


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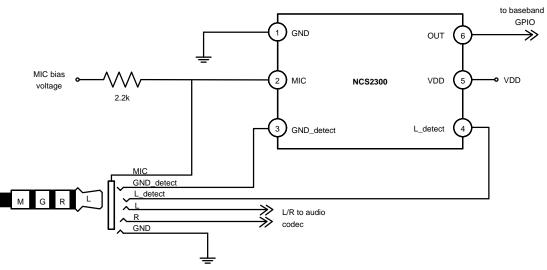
PIN DIAGRAM



ORDERING INFORMATION

Device	Package	Shipping [†]
NCS2300MUTAG	UDFN6 (Pb–Free)	3000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.





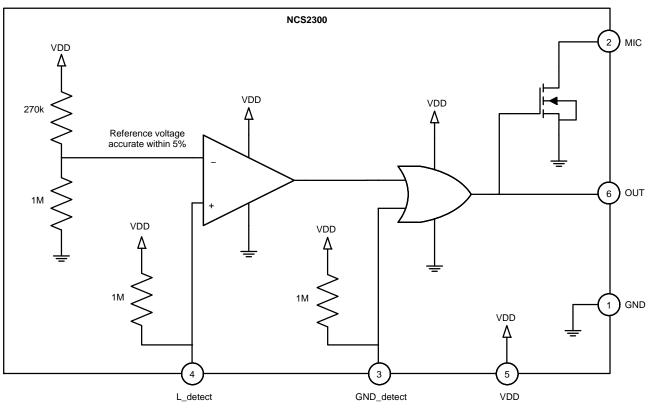


Figure 2. Block Diagram

Table 1. OUTPUT LOGIC

Inputs		Outputs		
L_detect	GND_detect	OUT	MIC	Headset
0	0	0	1 (external pull-up)	Detected
0	1	1	0	
1	0	1	0	Not Detected
1	1	1	0	

Table 2. PIN DESCRIPTION

Pin	Name	Туре	Description
1	GND	Power	GND is connected to the system ground.
2	MIC	Output	The open drain MIC output controls the bias on the MIC line. When the headset is not present, MIC is pulled low. When the headset is present, MIC is pulled up to the MIC bias voltage through an external pull–up resistor.
3	GND_detect	Input	GND_detect is the OR gate input. An internal 1 M Ω pull–up resistor pulls this pin high when the headset is not present.
4	L_detect	Input	L_detect is the comparator input. An internal 1 $M\Omega$ pull–up resistor pulls this pin high when the headset is not present.
5	VDD	Power	VDD is connected to the system power supply. A 0.1 μF decoupling capacitor is recommended as close as possible to this pin.
6	OUT	Output	OUT is a logic output that indicates whether the headset has been properly connected. OUT will be logic low only when GND_detect and L_detect are low.

Table 3. ABSOLUTE MAXIMUM RATINGS (Note 1)

Rating	Symbol	Value	Unit
Supply Voltage Range	V _{DD}	0 to 2.75	V
L_detect Input Pin Voltage Range	V _{L_detect}	–0.1 to V _{DD} + 0.1	V
GND_detect Input Pin Voltage Range	V _{GND_detect}	–0.1 to V _{DD} + 0.1	
MIC Output Pin Voltage Range	V _{MIC}	0 to 6.0	V
Maximum MIC Current	I _{MIC}	2	mA
Maximum Junction Temperature	T _{J(max)}	+125	°C
Storage Temperature Range	T _{stg}	-65 to +150	°C
ESD Capability (Note 2) Human Body Model Machine Model	ESD _{HBM} ESD _{MM}	5000 250	V
Latch-up Current (Note 3)	I _{LU}	800	mA
Moisture Sensitivity Level (Note 4)	MSL	Level 1	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

Refer to ELECTRICAL CHARACTERISTICS and APPLICATION INFORMATION for Safe Operating Area.
This device series incorporates ESD protection and is tested by the following methods: ESD Human Body Model tested per AEC-Q100-002 (JEDEC standard: JESD22-A114) ESD Machine Model tested per AEC-Q100-003 (JEDEC standard: JESD22-A115)
Latch-up Current tested per JEDEC standard: JESD78
Machine Model tested tested tested tested tested tested by the following methods:

4. Moisture Sensitivity Level tested per IPC/JEDEC standard: J-STD-020A

Table 4. OPERATING RANGES

Rating	Conditions	Symbol	Min	Тур	Max	Unit
Power Supply Voltage		V _{DD}	1.6	1.8	2.75	V
Input Voltage	L_detect and GND_detect pins	V _{IN}	0		V _{DD}	V
Input Transition Rise or Fall Rate	GND_detect pin	$\Delta t / \Delta V$	0		10	ns/V
Bias Voltage on MIC Output		V _{MIC}	0		3.0	V
Ambient Temperature		T _A	-40		85	°C
Junction Temperature		TJ	-40		125	°C

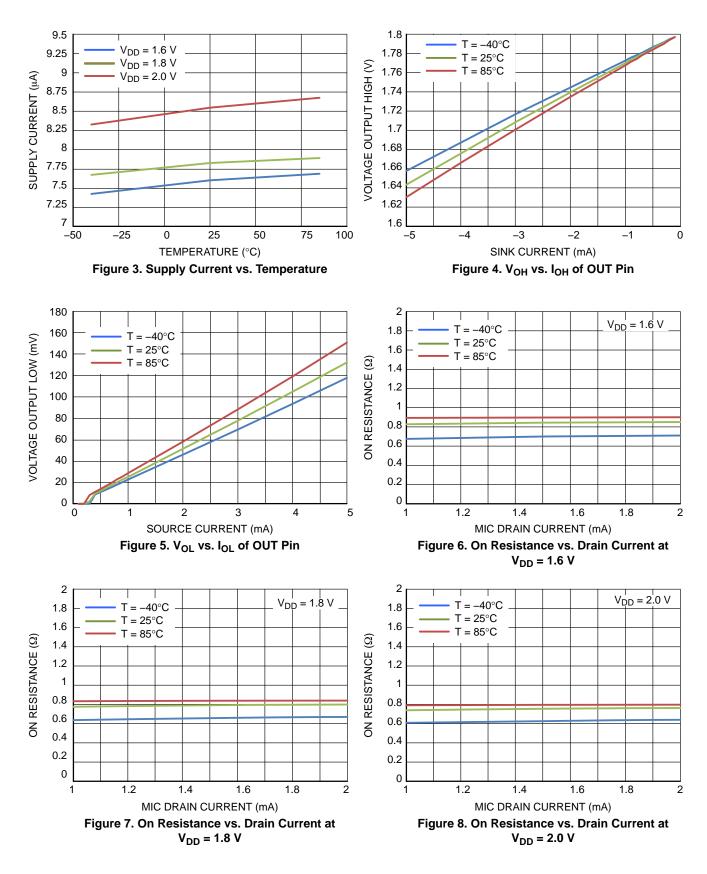
Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

Table 5. ELECTRICAL CHARACTERISTICS Typical values are referenced to $T_A = 25^{\circ}$ C, $V_{DD} = 1.8$ V, unless otherwise noted.
Min/max values apply from $T_A = -40^{\circ}$ C to 85°C, unless otherwise noted. (Note 5)

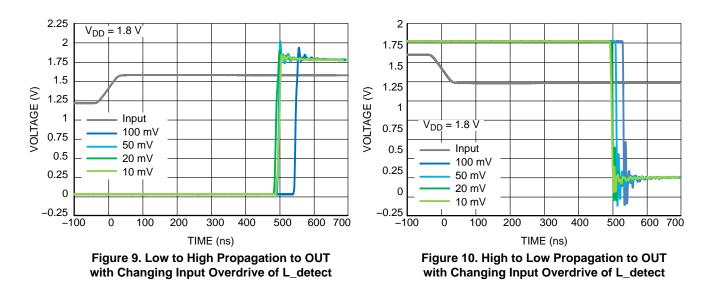
Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
SUPPLY CHARACTERISTICS						
Quiescent Supply Current	$V_{GND_detect} = 1.8 V \text{ or } 0 V$	I _{DD}		7.5	12	μΑ
INPUT CHARACTERISTICS OF L_DET	ECT					
Voltage Input Low	V _{DD} = 1.8 V	V _{IL}			1.33	V
Voltage Input High	V _{DD} = 1.8 V	V _{IH}	1.5			V
Propagation Delay to OUT	$C_{out} = 15 \text{ pF}, \text{GND_detect} = 0 \text{ V},$ L_detect = 1.31 V to 1.52 V	t _{pLH} , t _{pHL}		480		ns
Low Voltage Input Leakage	$V_{L_{detect}} = 0 V$	IIL		1.8		μΑ
High Voltage Input Leakage	$V_{L_{detect}} = 1.8 V$	I _{IH}		500		pА
Input Capacitance	f = 1 MHz	C _{IN}		3		pF
INPUT CHARACTERISTICS OF GND_I	DETECT					
Voltage Input Low	V _{DD} = 1.8 V	V _{IL}			0.63	V
Voltage Input High	V _{DD} = 1.8 V	V _{IH}	1.17			V
Propagation Delay to OUT	$C_{out} = 15 \text{ pF}, \text{ R}_{L} = 1 \text{ M}\Omega, \text{ L_detect} = 0 \text{ V}, \text{ GND_detect} = 0 \text{ to } 1.8 \text{ V}$	t _{pLH} , t _{pHL}		550		ps
Low Voltage Input Leakage	V _{GND_detect} = 0 V	Ι _{ΙL}		1.8		μA
High Voltage Input Leakage	V _{GND_detect} = 1.8 V	I _{IH}		500		pА
Input Capacitance	f = 1 MHz	C _{IN}		3		pF
OUTPUT CHARACTERISTICS OF OUT	-					
Voltage Output Low	$V_{DD} = 1.8 \text{ V}, \text{ I}_{OH} = 0.1 \text{ mA}$	V _{OL}			0.10	V
Voltage Output High	$V_{DD} = 1.8 \text{ V}, \text{ I}_{OH} = -0.1 \text{ mA}$	V _{OH}	1.70			V
Rise Time	C_{OUT} = 15 pF, R _L = 1 M Ω	t _{rise}		7		ns
Fall Time	C_{OUT} = 15 pF, R _L = 1 M Ω	t _{fall}		4		ns
CHARACTERISTICS OF MIC						
Drain-Source On Resistance of NMOS	V _{DD} = 1.8 V, I _{MIC} = 1 mA	R _{DS(on)}		0.9	1.4	Ω

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 5. Guaranteed by characterization and/or design.

TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS



APPLICATIONS INFORMATION

SUPPLY VOLTAGE

The NCS2300 works with a wide range of supply voltages from 1.6 V to 2.75 V. A 0.1 μ F decoupling capacitor should be placed as close as possible to the VDD pin. Since the NCS2300 has built in latch-up immunity up to 800 mA, series resistors are not recommended on VDD.

AUDIO JACK DETECTION

The NCS2300 is designed to simplify the detection of a stereo audio connector with a microphone contact. When the headset is not connected, the internal pull–up resistors on L_detect and GND_detect pull those pins high. When the headset is connected to the switched audio jack, the headset ground and left audio channel trigger L_detect and GND_detect to logic low.

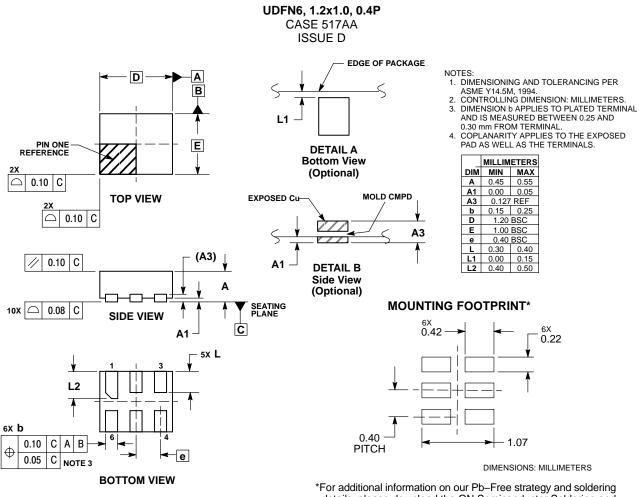
The NCS2300 can work with either the CTIA or OMTP standard. In order to support both standards simultaneously,

a cross point switch and additional circuitry is necessary to detect and swap the ground and microphone pins.

MIC PIN BIASING

The typical application schematic in Figure 1 shows the recommended 2.2 k Ω pull–up resistor to the MIC bias voltage. The MIC bias voltage can exceed VDD and can go as high as 3 V. While the headset is not detected, the internal NMOS transistor is enabled to mute the MIC signal. In the typical application scenario with a 2.2 k Ω pull–up to a 2.3 V MIC bias voltage, the MIC pin is pulled near 1 mV when the headset is not present. The internal NMOS transistor is optimized to sink up to 2 mA of current, allowing some flexibility in the selection of the pull–up resistor and MIC bias voltage.

PACKAGE DIMENSIONS



*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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